Application/Control No.	Applicant(s)/Patent under Reexamination		
10/553,452	LE CREFF ET AL		
Examiner	Art Unit		
Quynh H. Nguyen	2614		

	SEAR	CHED	
Class	Subclass	Date	Examiner
379	211.02 199 200	4/12/07	QN
370	522	4/12/07	QN
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOT (INCLUDING SEARCH		)
	DATE	EXMR
Searched: East, USPGPub, USPAT, JPO,EPO	4/12/07	QN
Inventor searched in PALM database	4/12/07	QN
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